

CEL  
CRITICAL ITEMS LIST  
FILE: CELB/1

NAME P/N QTY	CRIT	FAILURE MODE & CAUSES	FAILURE EFFECT	RATIONALE FOR ACCEPTANCE
REGULATOR, SCU WATER SUPPLY ITEM 489 SV772100-6 111  PC204-B *	Z/E	41999181: EXTERNAL LEAKAGE, RND ATTACHED.  CAUSE: DIAPHRAGM LEAKS OR RUPTURES, HOUSING SEAL LEAKAGE.	END ITEM: WATER LEAKAGE TO AMBIENT.  GPE INTERFACE: DEPLETION OF THE ORBITER WATER RESERVOIR.  MISSION: LOSS OF USE OF SCU  CREW/VEHICLE: NONE.	A. DESIGN - EXTERNAL LEAKAGE IS PREVENTED BY TWO RADIAL O-SEALS, A ROUNDED BEAD SEAL ON THE DIAPHRAGM DIA/CNFERENCE, AND THE DIAPHRAGM ITSELF. THE VITON O-SEALS HAVE A MIN SQUEEZE UNDER ALL TOLERANCE CONDITIONS OF 0.004 AND 0.007. THE SEALING SURFACES ON THE METAL PARTS HAVE 45 MICRON FINISH. THE BEAD SEAL ON THE SILASTIC 35 DIAPHRAGM HAS 0.004 MIN SQUEEZE. THE SEALING SURFACE ON THE METAL PARTS ARE A MATT FINISH COATED WITH TEFLON. THE DIAPHRAGM SPRING IS 0.052 AND THIS LIMITS DEFLECTION OF THE ELASTOMER TO 1/2. THE 10 DIAMETER SILICONE HAS ELONGATION CAPABILITY OF 500% WITHOUT DAMAGE.  B. TEST - COMPONENT ACCEPTANCE: EXTERNAL LEAKAGE IS CHECKED WITH AN IN-PROCESS TEST TO VERIFY NO LEAKS EXIST AT THE SPECIFIED 40 PSIG TEST POINT.  FOR: AN EXTERNAL LEAKAGE TEST IS PERFORMED WITH THE SCU MATED, PER 388U-40-005. WITH THE SCU MATED, THE PORTABLE WATER LINE INLET AND OUTLET PORTS ARE PRESSURIZED WITH WATER TO 30.5 - 41.5 PSIG FOR 60 MINUTES MINIMUM. NO EVIDENCE OF EXTERNAL LEAKAGE IS ALLOWED FROM ANY PART OF THE CIRCUIT.  CERTIFICATION: THE ITEM COMPLETED LEAKAGE TESTING TO 25 PSIG, AND PROOF PRESSURE TESTING TO 34.5 PSIG, AND WAS ANALYZED FOR ITS ACCEPTABILITY TO BURST PRESSURE (46 PSIG), DURING 1/82. THE FOLLOWING ENGINEERING CHANGES HAVE BEEN INCORPORATED AND CERTIFIED SINCE THAT TIME: 6208A-202 AND 202-1 (REVISED SCU MIN. OP. PRESS. TO 40 PSIG, PROOF PRESS TO 40 PSIG, AND BURST PRESS. TO 60 PSIG).

CIL  
 CRITICAL ITEMS LIST  
 FILE: CIL5/L

HWID P/N QTY	CRIT	FAILURE MODE & CAUSES	FAILURE EFFECT	RATIONALE FOR ACCEPTANCE
REGULATOR, SCU WATER SUPPLY ITEM 619 SV772190-6 411	2/2	0197M03A; EXTERNAL LEAKAGE, EMU ATTACHED.		<p>C. INSPECTION -          DIAPHRAGMS ARE VISUALLY INSPECTED AT IX TO ELIMINATE ANY VOIDS OR DEFECTS WHICH MIGHT CAUSE LEAKAGE OR RUPTURE FAILURE OF THE DIAPHRAGM. THE DIAPHRAGMS ARE MANUFACTURED FROM QUALITY APPROVED MOLDS WHICH ASSURE UNIFORMITY OF PRODUCTION PARTS. HOUSING SEALS (O RINGS) ARE CLEANED AND INSPECTED FOR CLEANLINESS TO MSJSD ENVISO LEVEL BEFORE INSTALLATION. AFTER ASSEMBLY THE O RINGS ARE VISUALLY REVIEWED FOR PROPER INSTALLATION AND TO MAKE SURE THAT NO DAMAGE DUE TO ASSEMBLY HAS BEEN DONE. THE DETAIL SEALING SURF AND O RING GROOVES ARE INSPECTED FOR SURFACE FINISH AND DIMENSION REQUIREMENTS TO ENSURE PROPER O RING SQUEEZE.</p> <p>D. FAILURE HISTORY -          NONE.</p> <p>E. GROUND TIGHTENING -          TESTED PER PRIM-R-001, ORBITER SCU CHECKOUT.</p> <p>F. OPERATIONAL USE -          POSIEVA (RECHARGE): TROUBLESHOOT PROBLEM. IF NO SUCCESS, USE OTHER SCU TO PERFORM EMU WATER DUMP AND CHARGE.          PREIEVA: TROUBLESHOOT PROBLEM. IF NO SUCCESS, DISCONTINUE USE OF SCU. OPERATE EMU ON BATTERY POWER. CONSIDER SHARING OTHER SCU FOR COOLING AND O2 IF BATTERY CONSTRAINTS PERMIT. CONSIDER BN-SUIT BATTERY SWAP USING SPARE BATTERY#1.          TRAINING - STANDARD EMU TRAINING COVERS THIS FAILURE MODE.          OPERATIONAL CONSIDERATIONS - AT LEAST ONE SPARE EMU BATTERY IS MANIFESTED FOR EACH FLIGHT. EVA CHECKLIST PROCEDURES VERIFY HARDWARE INTEGRITY AND SYSTEMS OPERATIONAL STATUS PRIOR TO EVA.</p>
YC144-2 "				